

Notice of References Cited	Application/Control No. 10/762,479	Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Jack Smith	Art Unit 1709	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	K.W. Park, K.S. Ahn, J.H. Choi, Y.C. Nah, Y.M. Kim, "Pt-WOx electrode structure for thin-film fuel cells," Applied Physics Letters 81, (2002) 907-909.
	V	D. Gogva, K. Gesheva, A. Szekeres and M. Sendova-Vassileva, "Structural and Optical Properties of CVD Thin Tungsten Oxide Films," Physica Status Solidi (a) 176 (2) , (1999) 969 - 984.
	W	S. Pruneanu, G. Mihailescu, E. Indrea, "Nanoporous Al2O3 membranes filled by platinum," Semiconductor Conference 2000, CAS 2000 Proceedings, International 2, (2000) 475-478.
	X	T.J. Vink, W. Walrave, J.L.C. Daams, P.C. Baarslag, J.E.A.M. van den Meerakker, "On the homogeneity of sputter-deposited ITO films Part I. Stress and microstructure," Thin Solid Films 266 (1995) 145-151.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.